

April 2009

# MOC205M, MOC206M, MOC207M, MOC208M Small Outline Optocouplers Transistor Output

# Features

- U.L. recognized (File #E90700, Volume 2)
- VDE recognized (File #136616) (add option "V" for VDE approval, i.e, MOC205VM)
- Closely matched current transfer ratios
- Convenient plastic SOIC-8 surface mountable package style
- Minimum BV<sub>CEO</sub> of 70 Volts guaranteed
- Standard SOIC-8 footprint, with 0.050" lead spacing
- Compatible with dual wave, vapor phase and IR reflow soldering
- High input-output isolation of 2500 V<sub>AC(rms)</sub> guaranteed

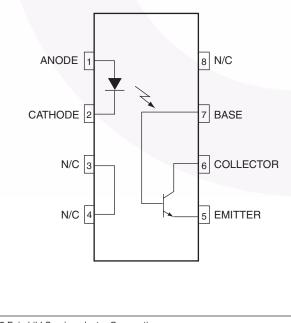
# Applications

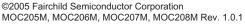
- Feedback control circuits
- Interfacing and coupling systems of different potentials and impedances
- General purpose switching circuits
- Monitor and detection circuits

# Description

These devices consist of a gallium arsenide infrared emitting diode optically coupled to a monolithic silicon phototransistor detector, in a surface mountable, small outline, plastic package. They are ideally suited for high density applications, and eliminate the need for throughthe-board mounting.

# Schematic





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## Absolute Maximum Ratings (T<sub>A</sub> = 25°C Unless otherwise specified)

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Rating	Value	Unit
EMITTER			1
I <sub>F</sub>	Forward Current – Continuous	60	mA
l <sub>F</sub> (pk)	Forward Current – Peak (PW = 100µs, 120pps)	1.0	A
V <sub>R</sub>	Reverse Voltage	6.0	V
P <sub>D</sub>	LED Power Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	90 0.8	mW mW/°C
DETECTOR			1
V <sub>CEO</sub>	Collector-Emitter Voltage	70	V
V <sub>ECO</sub>	Emitter-Collector Voltage	7.0	V
V <sub>CBO</sub>	Collector-Base Voltage	70	V
Ι <sub>C</sub>	Collector Current-Continuous	150	mA
P <sub>D</sub>	Detector Power Dissipation @ $T_A = 25^{\circ}C$ Derate above 25°C	150 1.76	mW mW/°C
TOTAL DEVICE			
V <sub>ISO</sub>	Input-Output Isolation Voltage (f = 60Hz, t = 1 min.) <sup>(1)(2)(3)</sup>	2500	Vac(rms)
P <sub>D</sub>	Total Device Power Dissipation @ $T_A = 25^{\circ}C$ Derate above 25°C	250 2.94	mW mW/°C
T <sub>A</sub>	Ambient Operating Temperature Range	-40 to +100	°C
T <sub>stg</sub>	Storage Temperature Range	-40 to +150	°C

### Notes:

1. Isolation Surge Voltage, VISO, is an internal device dielectric breakdown rating.

2. For this test, Pins 1 and 2 are common and Pins 5, 6 and 7 are common.

3.  $V_{ISO}$  rating of 2500  $V_{AC(rms)}$  for t = 1 min. is equivalent to a rating of 3,000  $V_{AC(rms)}$  for t = 1 sec.

Symbol	Parameter	Test Conditions	Min.	Тур.*	Max.	Unit
EMITTER						
V <sub>F</sub>	Input Forward Voltage	I <sub>F</sub> = 10mA		1.15	1.5	V
Ι <sub>R</sub>	Reverse Leakage Current	V <sub>R</sub> = 6.0V		0.001	100	μA
C <sub>IN</sub>	Input Capacitance			18		pF
DETECTO	DR					
I <sub>CEO1</sub> I <sub>CEO2</sub>	Collector-Emitter Dark Current	$V_{CE} = 10V, T_A = 25^{\circ}C$ $V_{CE} = 10V, T_A = 100^{\circ}C$		1.0 1.0	50	nA μA
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	I <sub>C</sub> = 100μA	70	100		V
BV <sub>ECO</sub>	Emitter-Collector Breakdown Voltage	I <sub>E</sub> = 100μA	7.0	10		V
C <sub>CE</sub>	Collector-Emitter Capacitance	f = 1.0 MHz, V <sub>CE</sub> = 0		7.0		pF
COUPLE	D					
CTR	Collector-Output Current <sup>(4)</sup> MOC205M MOC206M MOC207M MOC208M1	I <sub>F</sub> = 10mA, V <sub>CE</sub> = 10V	40 63 100 40		80 125 200 125	%
V <sub>ISO</sub>	Isolation Surge Voltage <sup>(1)(2)(3)</sup>	f = 60 Hz AC Peak, t = 1 min.	2500			Vac(rms
R <sub>ISO</sub>	Isolation Resistance <sup>(2)</sup>	V = 500V	10 <sup>11</sup>			Ω
V <sub>CE (sat)</sub>	Collector-Emitter Saturation Voltage	$I_{\rm C} = 2mA, I_{\rm F} = 10mA$			0.4	V
C <sub>ISO</sub>	Isolation Capacitance <sup>(2)</sup>	V = 0V, f = 1MHz		0.2		pF
t <sub>on</sub>	Turn-On Time	$I_{C} = 2.0 \text{mA}, V_{CC} = 10 \text{ V}, R_{L} = 100 \Omega \text{ (Fig. 6)}$		7.5		μs
t <sub>off</sub>	Turn-Off Time	$I_{C} = 2.0 \text{mA}, V_{CC} = 10 \text{V},$ $R_{L} = 100 \Omega \text{ (Fig. 6)}$		5.7		μs
t <sub>r</sub>	Rise Time	$I_{C} = 2.0 \text{mA}, V_{CC} = 10 \text{V},$ $R_{L} = 100 \Omega \text{ (Fig. 6)}$		3.2		μs
t <sub>f</sub>	Fall Time	$I_{C} = 2.0 \text{ mA}, V_{CC} = 10 \text{ V},$ $R_{L} = 100\Omega \text{ (Fig. 6)}$		4.7		μs

\*Typical values at  $T_A = 25^{\circ}C$ 

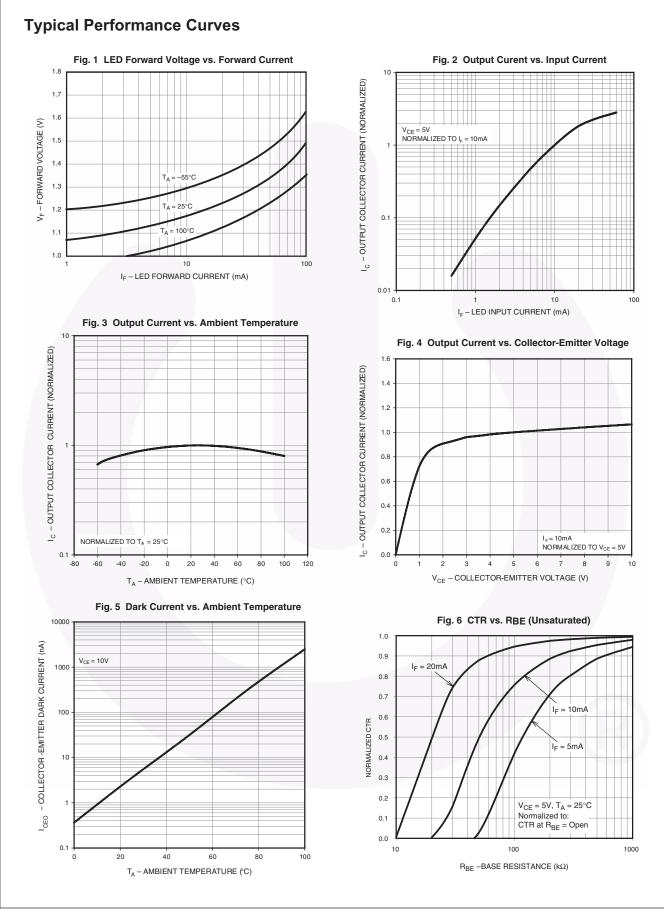
### Notes:

1. Isolation Surge Voltage,  $V_{\mbox{\scriptsize ISO}},$  is an internal device dielectric breakdown rating.

2. For this test, Pins 1 and 2 are common and Pins 5, 6 and 7 are common.

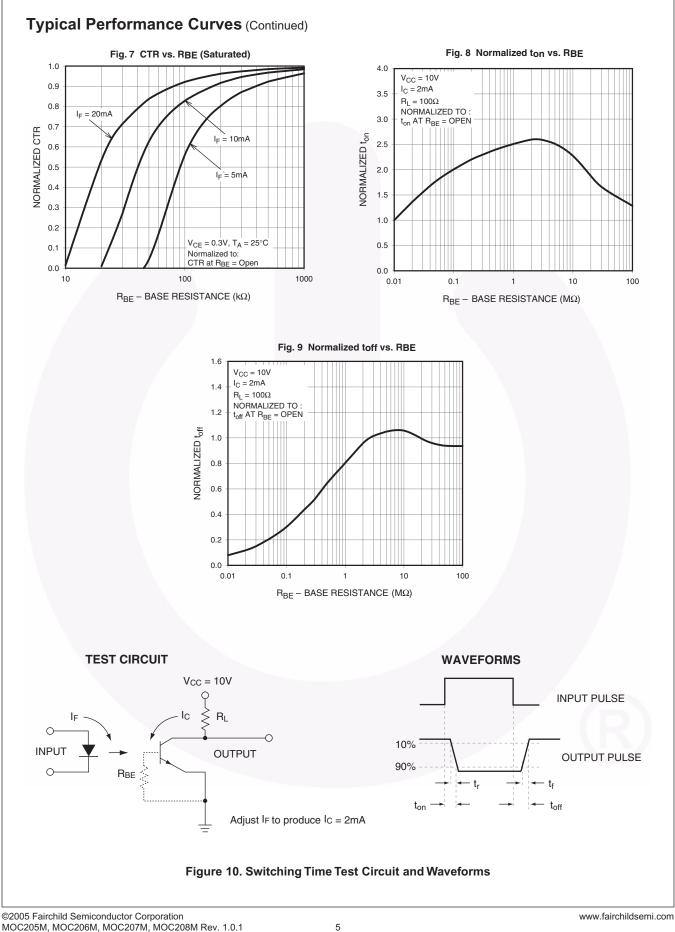
3.  $V_{ISO}$  rating of 2500  $V_{AC(rms)}$  for t = 1 min. is equivalent to a rating of 3,000  $V_{AC(rms)}$  for t = 1 sec.

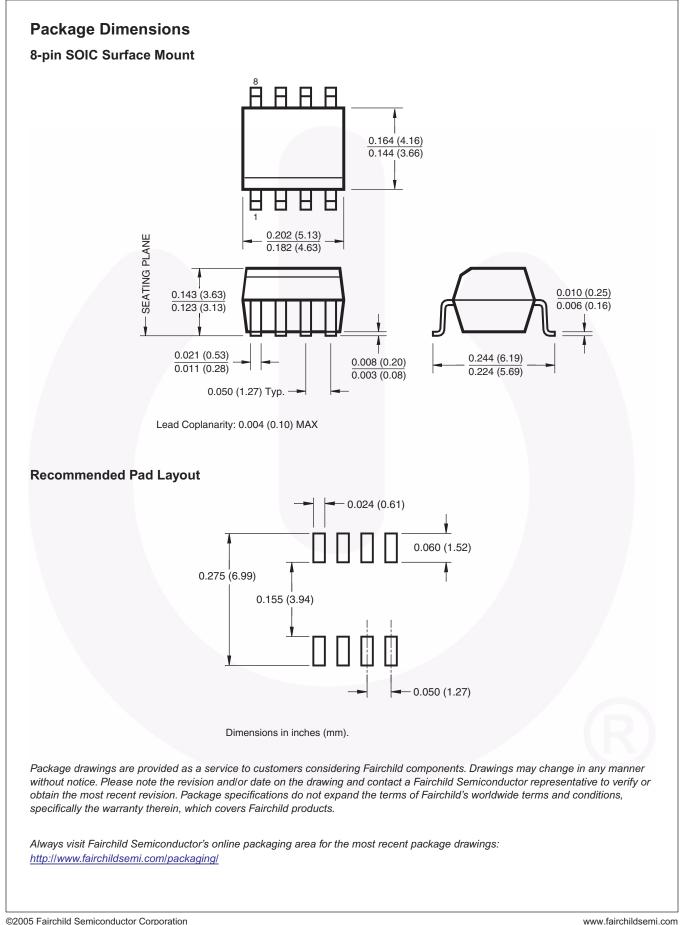
4. Current Transfer Ratio (CTR) =  $I_C/I_F \times 100\%$ .



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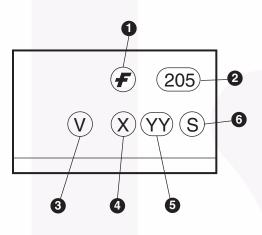


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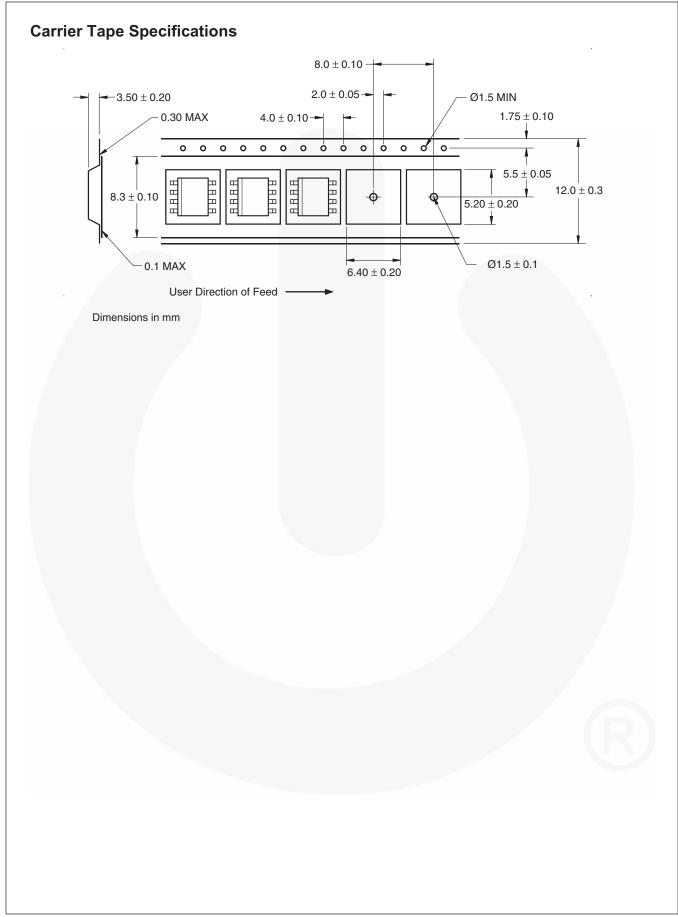
# **Ordering Information**

Option	Order Entry Identifier	er Description	
V	V	VDE 0884	
R2	R2	R2 Tape and reel (2500 units per reel)	
R2V	R2V	VDE 0884, Tape and reel (2500 units per reel)	

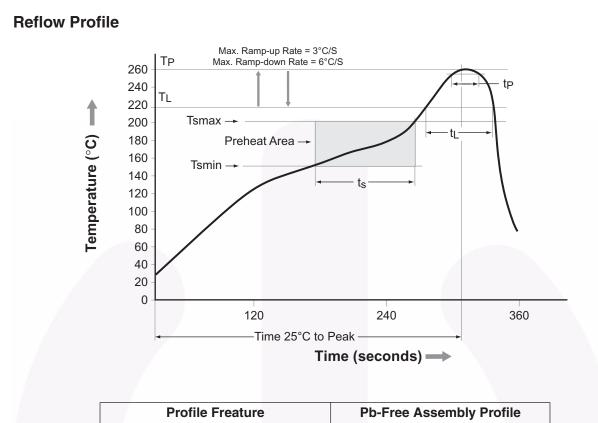
# **Marking Information**



# Definitions1Fairchild logo2Device number3VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table)4One digit year code, e.g., '8'5Two digit work week ranging from '01' to '53'6Assembly package code



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Profile Freature	Pb-Free Assembly Profile
Temperature Min. (Tsmin)	150°C
Temperature Max. (Tsmax)	200°C
Time (t <sub>S</sub> ) from (Tsmin to Tsmax	() 60–120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217°C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub>	) 60–150 seconds
Peak Body Package Temperatu	re 260°C +0°C / -5°C
Time (t <sub>P</sub> ) within 5°C of 260°C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max.
Time 25°C to Peak Temperatur	e 8 minutes max.

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9



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Datasheet Identification Product Status		Definition	
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Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.	
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